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Question Paper Code: 34402

B.E. / B.Tech. DEGREE EXAMINATION, NOV 2018

Fourth Semester

Computer Science and Engineering

01UCS402 - SOFTWARE TESTING

(Regulation 2013)

Duration: Three hours

Maximum: 100 Marks

Answer ALL Questions.

PART A - (10 x 2 = 20 Marks)

1. Differentiate verification and validation.
2. List any two classification of defect.
3. What is the purpose of negative testing?
4. List the methods of White box testing.
5. List the issues of class testing.
6. What are the advantages of bottom up integration?
7. Define Work Breakdown Structure (WBS).
8. Write down the skills needed by a Test specialist.
9. Define Defect Removal Leverage (DRL).
10. What are the various types of reviews and its need?

PART - B (5 x 16 = 80 Marks)

11. (a) (i) Explain in detail the various software testing principles. (8)
(ii) Explain the process of defect repository development. (8)

Or

- (b) Explain the origin of defect and its classes with its repository in detail. (16)

12. (a) Explain the concept of equivalence class partitioning and boundary value analysis with example. (16)

Or

- (b) (i) What is Equivalence class partitioning? List rules used to define valid and invalid equivalence classes. Explain the technique using an example. (8)

- (ii) What is Boundary value analysis? Explain the technique specifying rules and its usage with the help of an example. (8)

13. (a) List and explain the various types of system testing with examples. (16)

Or

- (b) How the salient aspects of object orientation affect software testing? Explain the differences in object oriented testing. (16)

14. (a) Discuss on the test infrastructure management with suitable example. (16)

Or

- (b) (i) Discuss testing team structure for single product companies. (10)

- (ii) What are the skills needed for a test specialist? Explain in detail. (6)

15. (a) Discuss the significance of various measurements and milestones for monitoring and controlling in the testing process. (16)

Or

- (b) Explain in detail about test defect metrics and its measurements. (16)